

Docket No.: 296431US2PCT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION: Hisao IGARASHI, et al.

SERIAL NO.: 10/593,830

GAU: 2829

FILED: September 22, 2006

EXAMINER: TANG, MINH NHUT

FOR: PROBE APPARATUS, WAFER INSPECTING APPARATUS PROVIDED WITH THE
PROBE APPARATUS AND WAFER INSPECTING METHOD

LETTER SUBMITTING REPLACEMENT DRAWING SHEET(S)

COMMISSIONER FOR PATENTS
Alexandria, VA 22313

SIR:

Responsive to the below indicated communication, the following drawing sheets are submitted herewith:

☒ 1 Replacement Drawing Sheets ☐ _____ New Drawing Sheets
☐ _____ Annotated Drawing Sheets

☒ Official Action dated February 28, 2008
☐ Notice of Allowance/Issue Fee dated _____
☐ Other dated _____

The changes and/or modifications made include the following:

Legend "Background Art" has been added to Figure 17.

Respectfully Submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.



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